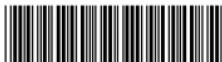


Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10577896	HACK ET AL.
Examiner	Art Unit	
ALEXANDER C WITKOWSKI	2853	

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
Stephen D. Meier, Supervisory Patent Examiner.	09/21/2008	ACW
Limited classification search: 347/ 47	09/21/2008	ACW
Text search; see search history.	09/21/2008	ACW

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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